

Low-Noise and Low-Voltage Circuit Techniques for CMOS Analog Design

Takeshi Yoshida, Yoshihiro Masui, Mamoru Sasaki, Atsushi Iwata
Hiroshima University

Outline

1. Introduction
2. Basic concept
 - Low-voltage technique
 - Low-noise technique
3. Low-noise amplifier
4. Low-voltage SA ADC
5. Summary

Introduction

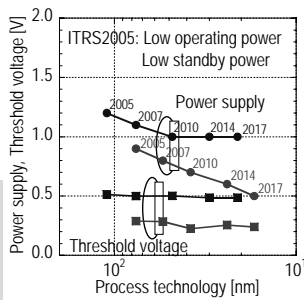
CMOS technology innovation

Advantage

- High-speed operation
- Lower power consumption
- Shrinking chip area

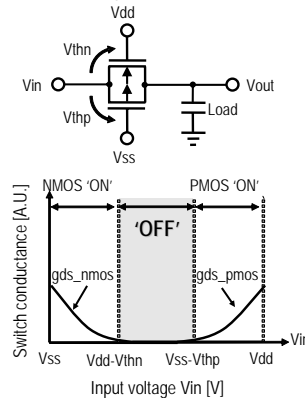
Disadvantage

- Power supply voltage reduction
 - Analog switch issue
 - S/N deterioration
- V_{th} variation
- $1/f$ noise

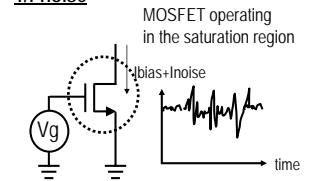


Issues of CMOS analog design

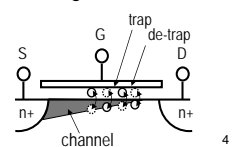
CMOS analog switch



$1/f$ noise



Large $1/f$ noise



Objectives

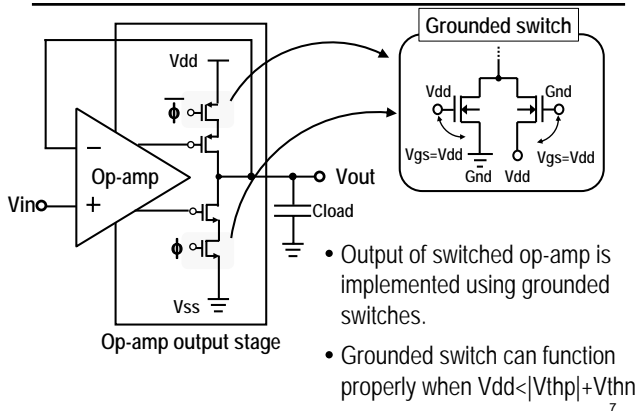
Proposals for low-voltage and low-noise circuit techniques to realize a CMOS analog design in a state of the art process technology.

- Noise reduction →
 - Autozeroing
 - Chopper stabilization
- Low voltage →
 - Switched op-amp
 - Grounded switch
 - Rail-to-rail signal swing

Outline

1. Introduction
2. Basic concept
 - ➡ ▪ Low-voltage technique
 - Low-noise technique
3. Low-noise amplifier
4. Low-voltage SA ADC
5. Summary

Grounded switch

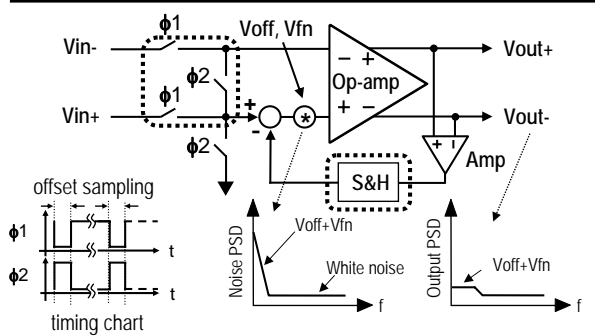


Outline

1. Introduction
2. Basic concept
 - Low-voltage technique
- ⇒ 3. Low-noise amplifier
4. Low-voltage SA ADC
5. Summary

8

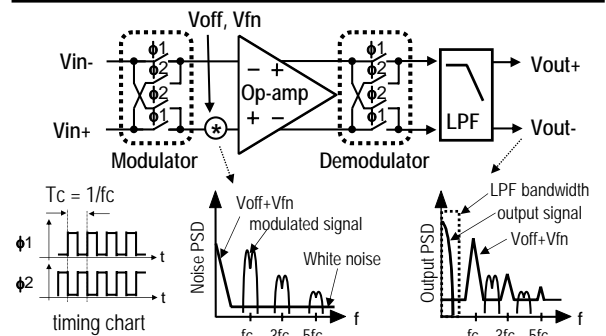
Autozeroing



- Increment of baseband noise floor
- Bootstrap technique or low- V_{th} device is required

9

Chopper stabilization



- Large noise power remains at a chopping frequency
- Bootstrap technique or low- V_{th} device is required

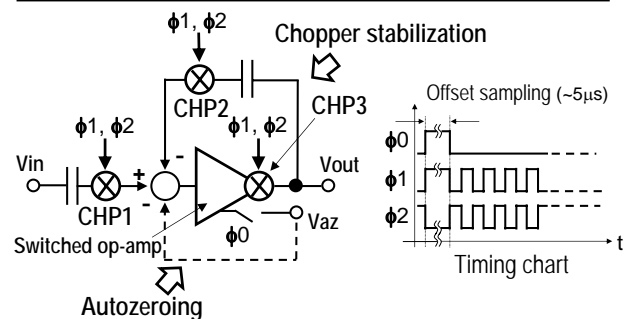
10

Outline

1. Introduction
2. Basic concept
 - Low-voltage technique
 - Low-noise technique
- ⇒ 3. Low-noise amplifier
4. Low-voltage SA ADC
5. Summary

11

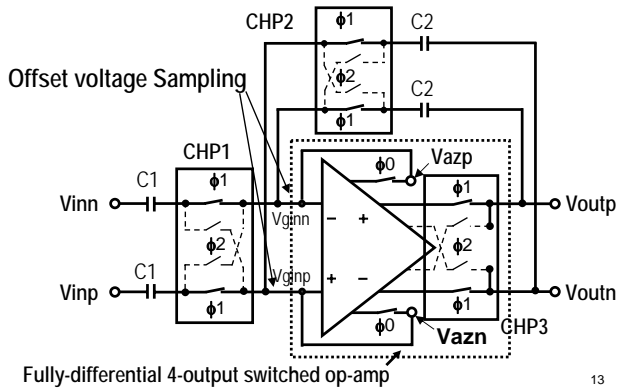
Low-noise low-voltage amp: Concept



- Switches (CHP1,2) in the virtual ground
- Chopper (CHP3) implemented by switched op-amp
- Use both noise reduction techniques

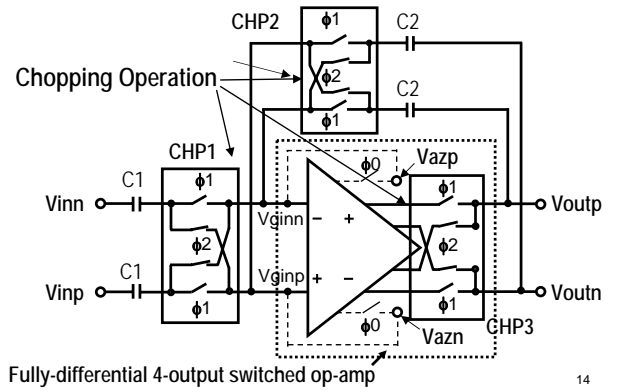
12

Proposed autozeroing technique



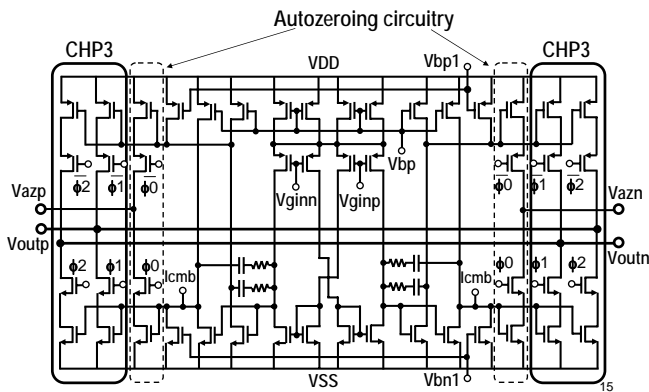
13

Proposed chopper stabilization



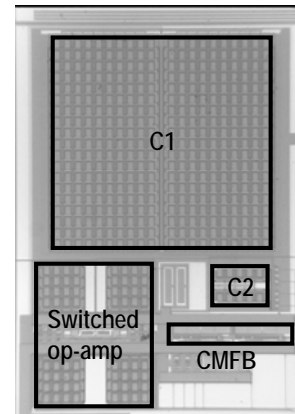
14

Switched op-amp



15

Chip micrograph



Process

0.18 μ m CMOS,
1-Poly/6-Metal/MiM-Cap
0.42V:NMOS Vth
0.5V:PMOS Vth

Supply Voltage

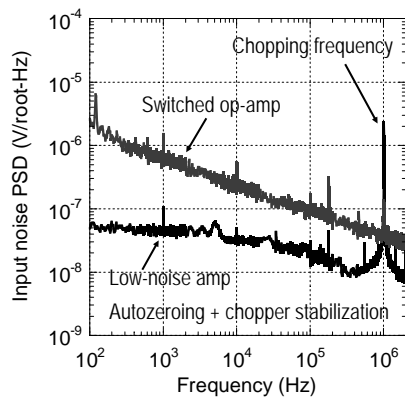
1V

Area

800 x 1100 μ m²

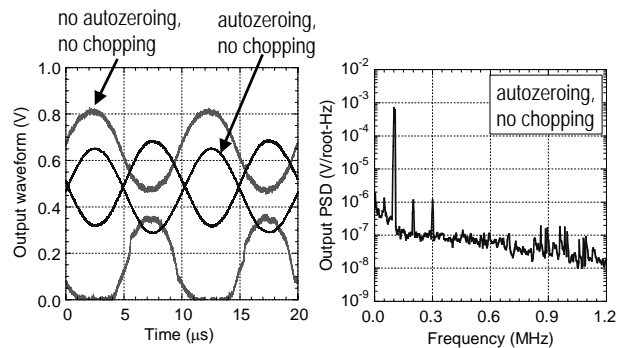
16

Input noise PSD



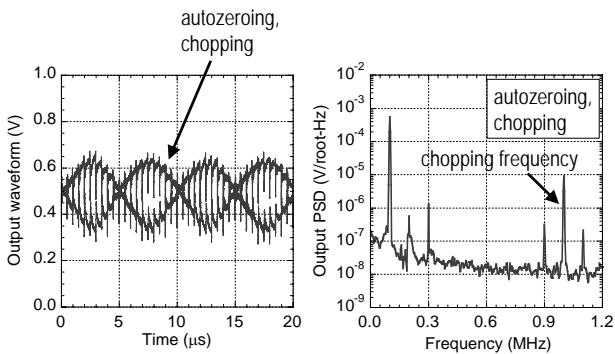
17

Amplifier output 1/2



18

Amplifier output 2/2



19

Comparison of amplifier performances

	This work	ISSCC2002[1]	JSSC2000[2]
Supply voltage (V)	1.0	5.0	1.0
Autozeroing frequency (kHz)	< 0.001	7.5	-
Chopping frequency (kHz)	1000	15	-
Input noise PSD (nV/√Hz)	50	20	360
Power consumption (mW)	0.5	4.0	0.2
Chip area (mm ²)	0.88	0.67	0.81
FOMx10 ³	45	18.7	17.1

$$\text{Figure of Merit} = \frac{1}{\text{Noise PSD} \times \text{Power} \times \text{Area}}$$

[1] A. T. K. Tang, "A 3 μ V-Offset Operational Amplifier with 20nV/√Hz Input Noise PSD at DC Employing both Chopping and Autozeroing", IEEE ISSCC Digest of Technical Papers, pp.386-387, Feb.2002.
 [2] J. F. Duque-Carrillo et al., "1-V Rail-to-Rail Operational Amplifiers in Standard CMOS Technology", IEEE Journal of Solid State Circuits, vol.35, No. 1, pp.33-44, Jan 2000.

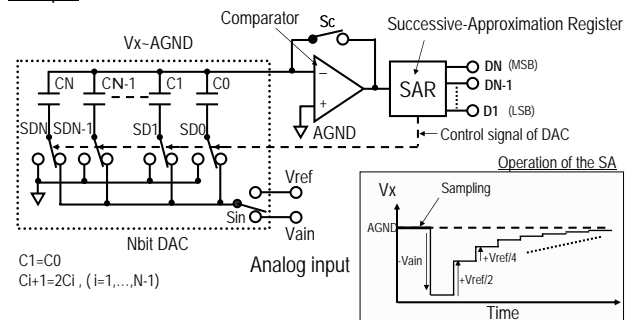
Outline

1. Introduction
2. Basic concept
 - Low-voltage technique
 - Low-noise technique
3. Low-noise amplifier
- ➡ 4. Low-voltage SA ADC
5. Summary

21

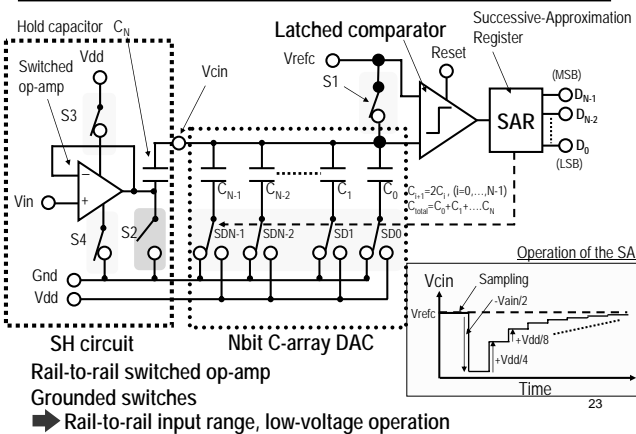
SA ADC based on charge-redistribution

Sample



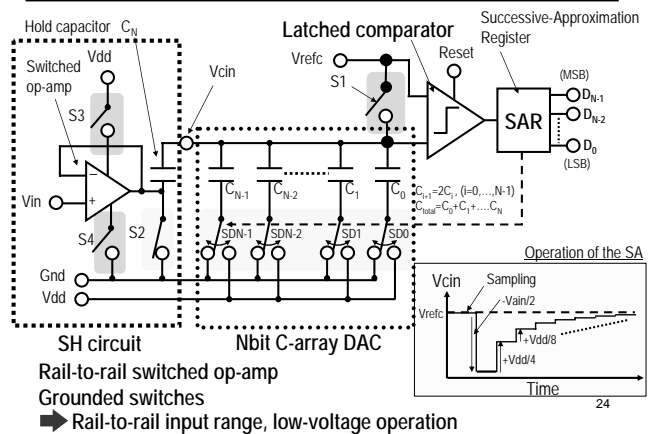
CMOS analog switches can't function properly when $V_{dd} < |V_{thp}| + V_{thn}$ 22

Proposed SA ADC with rail-to-rail input



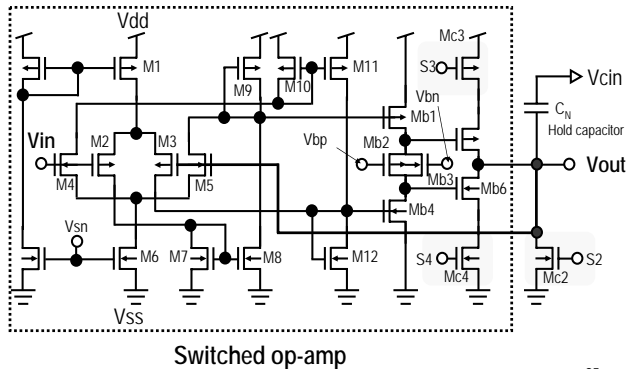
23

Proposed SA ADC with rail-to-rail input



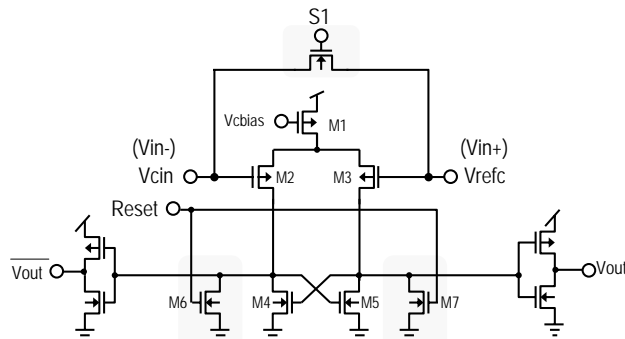
24

Sample and hold circuit



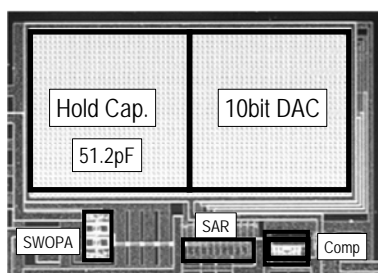
25

Latched comparator



26

Chip micrograph



Technology

0.18um CMOS Process
1P 6M MIM-Cap
 V_{thn} : 0.42V
 $|V_{thp}|$: 0.50V

Chip area

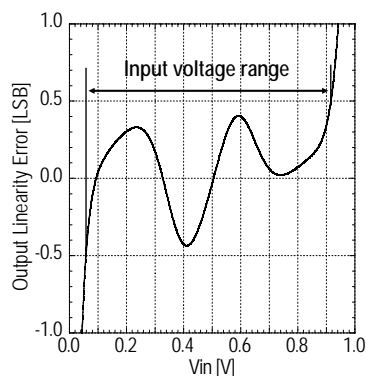
1.25 x 0.85 mm²

Supply voltage

1 V

27

Linearity error of SH circuit

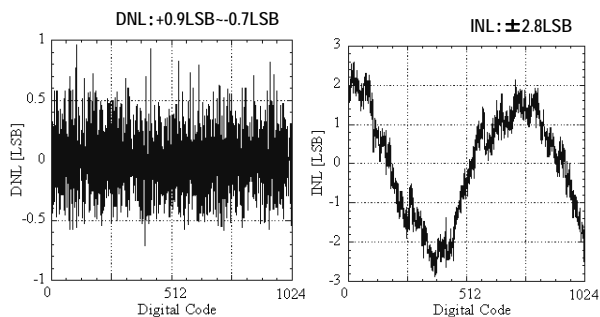


Specifications

Linearity error: +/-0.25mV
Input range: 0.05V-0.9V
Power: 170uW
Supply voltage: 1V

28

Differential and Integral nonlinearities



Sampling rate: 400kSps
Input voltage range: 50mV-870mV

29

Comparison of ADC performance

	This work	JSSC 2000[1]	JSSC 2001[2]
Supply voltage (V)	1.0	1.0	5.0
Resolution (bit)	10	8	12
Sampling rate (kSps)	400	50	1000
Power consumption (mW)	0.20	0.34	15
Chip area (mm ²)	1.0	3.24	1.5
FOM	2048	37.6	273

Figure-of-Merit defined by: $\frac{2^n \cdot \text{Sampling Rate}}{\text{Power}}$

[1] S. Mortezaipour et al, "A 1-V, 8-Bit Successive Approximation ADC in Standard CMOS Process", JSSC, vol.35, pp.642-250646, April 2000.
[2] G. Promitzer, "12-b Low-Power Fully Differential Switched Capacitor Noncalibrating Successive Approximation ADC with 1MS/s", JSSC, vol.36, pp.1138-1143, July 2001.

30

Outline

1. Introduction
2. Basic concept
 - Low-voltage technique
 - Low-noise technique
3. Low-noise amplifier
4. Low-voltage SA ADC
- ⇒ 5. Summary

31

Summary

Low-noise and low-voltage circuit techniques are presented

Key technique:

Autozeroing and chopper stabilization

Multi-output switched op-amp

Grounded switch

Rail-to-rail input range

- Low-noise amp achieved $50\text{nV}/\sqrt{\text{Hz}}$ noise PSD, 52dB THD and 88dB DR at 1V supply voltage
- 10bit SA ADC achieved 400kS/s sampling rate, 200uW power dissipation at 1V supply voltage ³²